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(12) United States Design Patent

Okajima et al.

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(54) **SUPPORTING COLUMN OF INSULATION UNIT FOR SEMICONDUCTOR MANUFACTURING APPARATUS**

(71) Applicant: **KOKUSAI ELECTRIC CORPORATION**, Tokyo (JP)

(72) Inventors: **Yusaku Okajima**, Toyama (JP); **Shuhei Saido**, Toyama (JP); **Hidenari Yoshida**, Toyama (JP)

(73) Assignee: **KOKUSAI ELECTRIC CORPORATION**, Tokyo (JP)

(**) Term: **15 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (13) Cl.** **13-03**

(52) **U.S. Cl.**
USPC **D13/184**

(58) **Field of Classification Search**
USPC D8/356, 349, 380, 373, 354, 366; D13/151, 182, 184
CPC C30B 25/14; H01L 21/67017; C23C 16/4412; C23C 16/45578; C23C 16/44; C23C 16/455
See application file for complete search history.

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Primary Examiner — Keli L Hill
Assistant Examiner — Harold E Blackwell, II
(74) *Attorney, Agent, or Firm* — Fitch, Even, Tabin & Flannery, LLP

(57) **CLAIM**

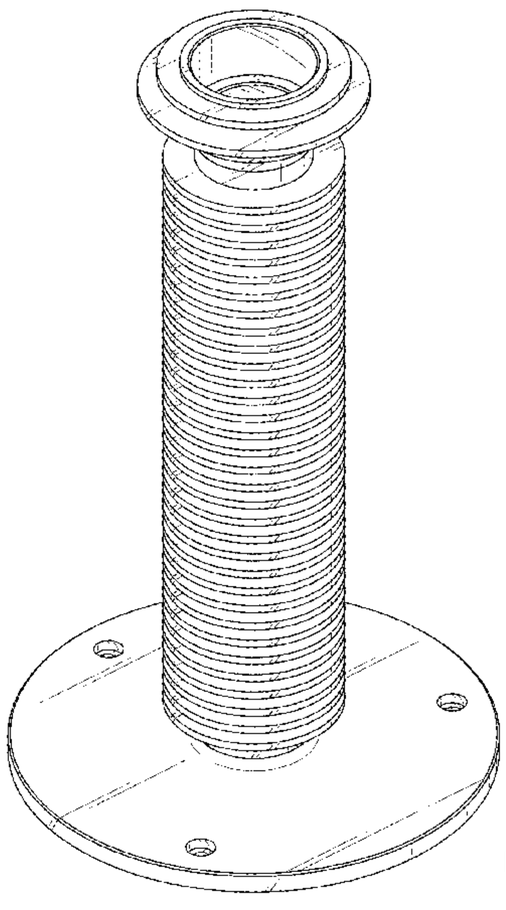
The ornamental design for a supporting column of insulation unit for semiconductor manufacturing apparatus, as shown (and described).

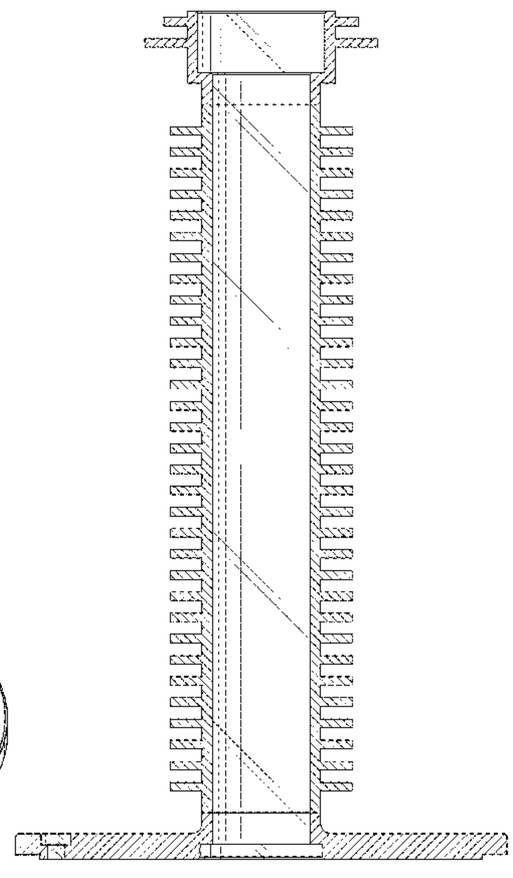
DESCRIPTION

FIG. **1** is a front, top and right side perspective view of a supporting column of insulation unit for semiconductor manufacturing apparatus showing our new design;
FIG. **2** is a front elevational view thereof;
FIG. **3** is a rear elevational view thereof;
FIG. **4** is a right side elevational view thereof;
FIG. **5** is a left side elevational view thereof;
FIG. **6** is a top plan view thereof;
FIG. **7** is a bottom plan view thereof; and,
FIG. **8** is a cross-sectional view take along line **8-8** in FIG. **2**.

The dot-dash broken lines FIG. **2** are for reference purposes only; the broken lines form no part of the claimed design.

1 Claim, 7 Drawing Sheets





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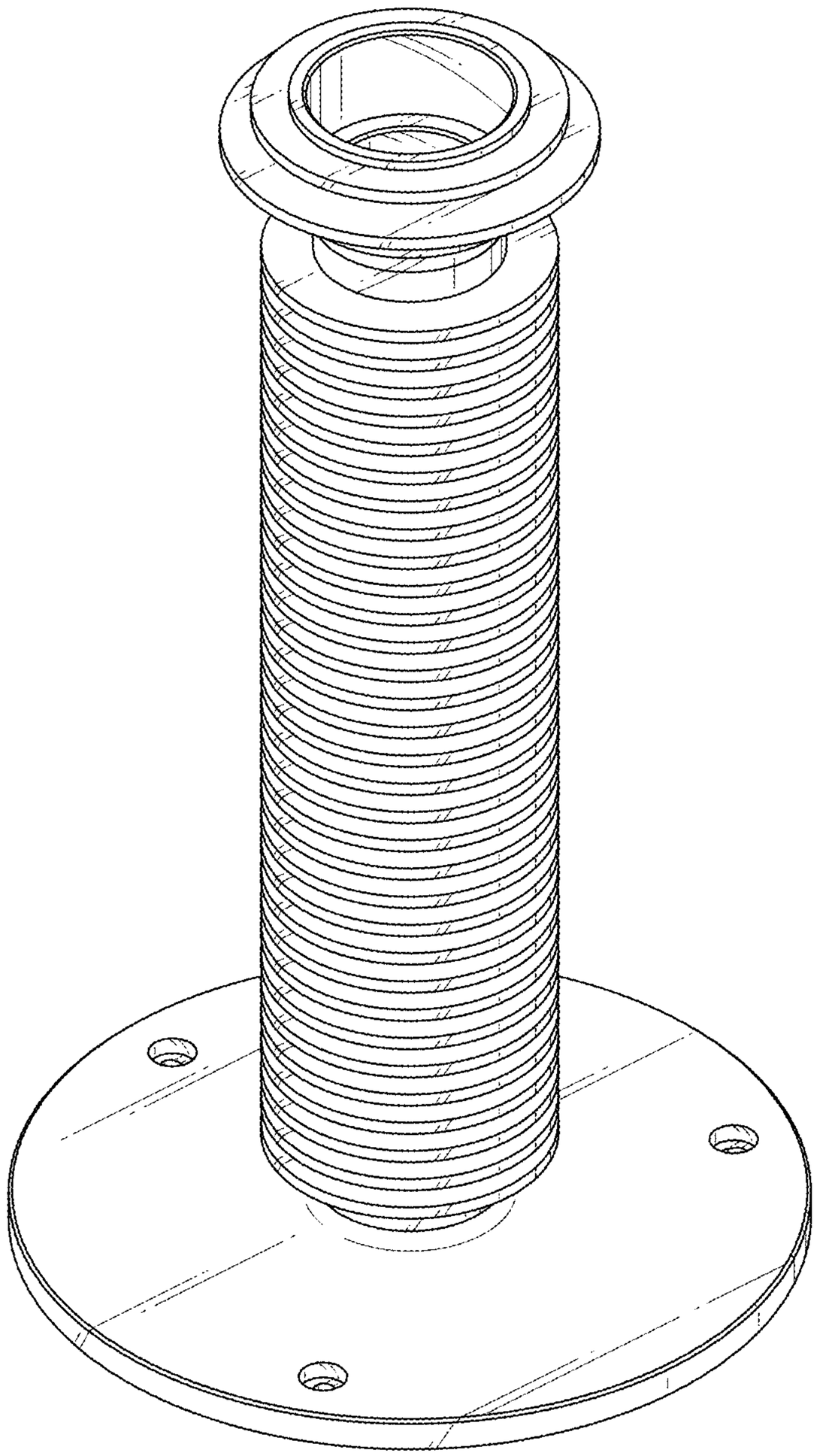

FIG. 1

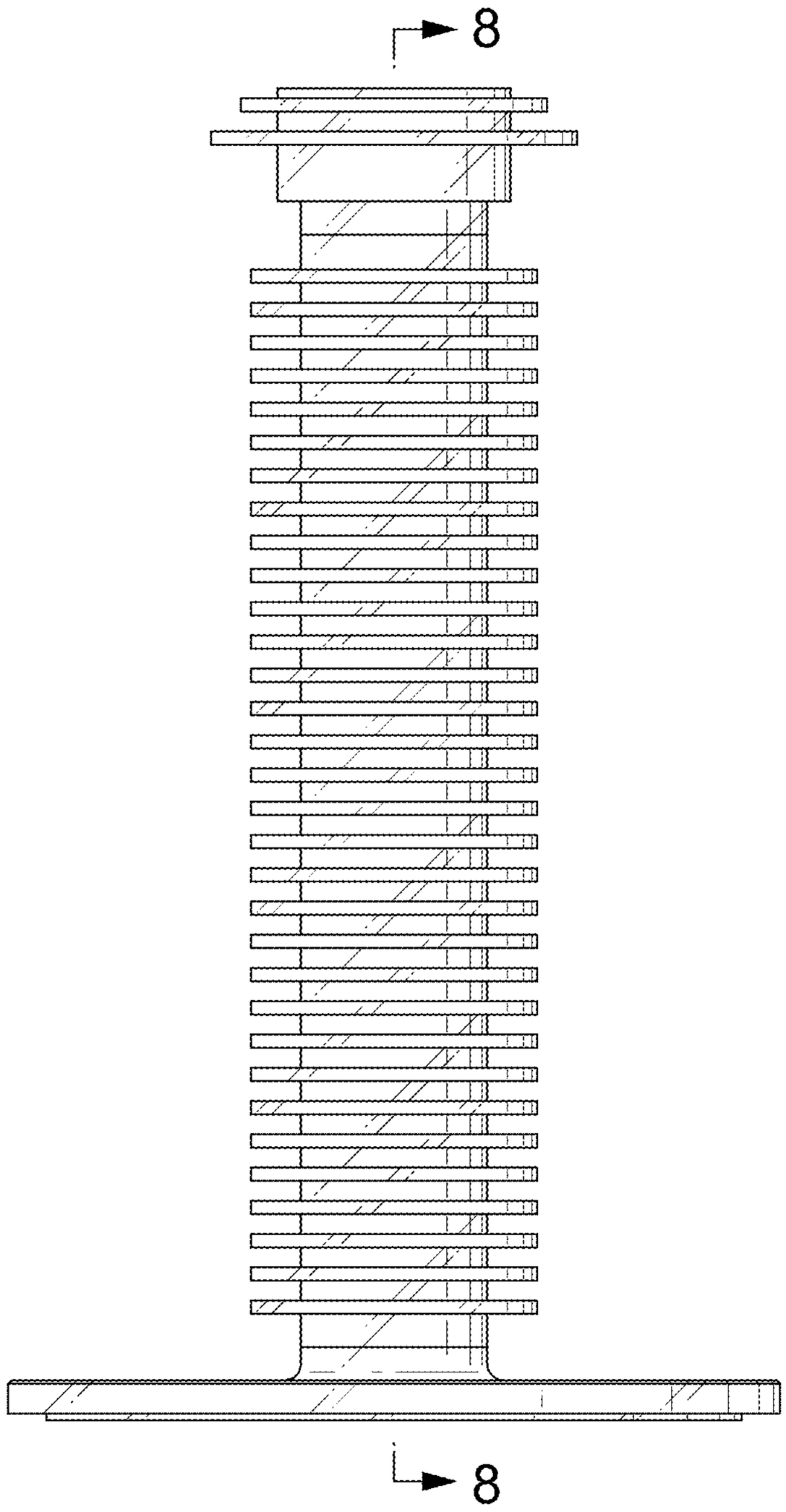

FIG. 2

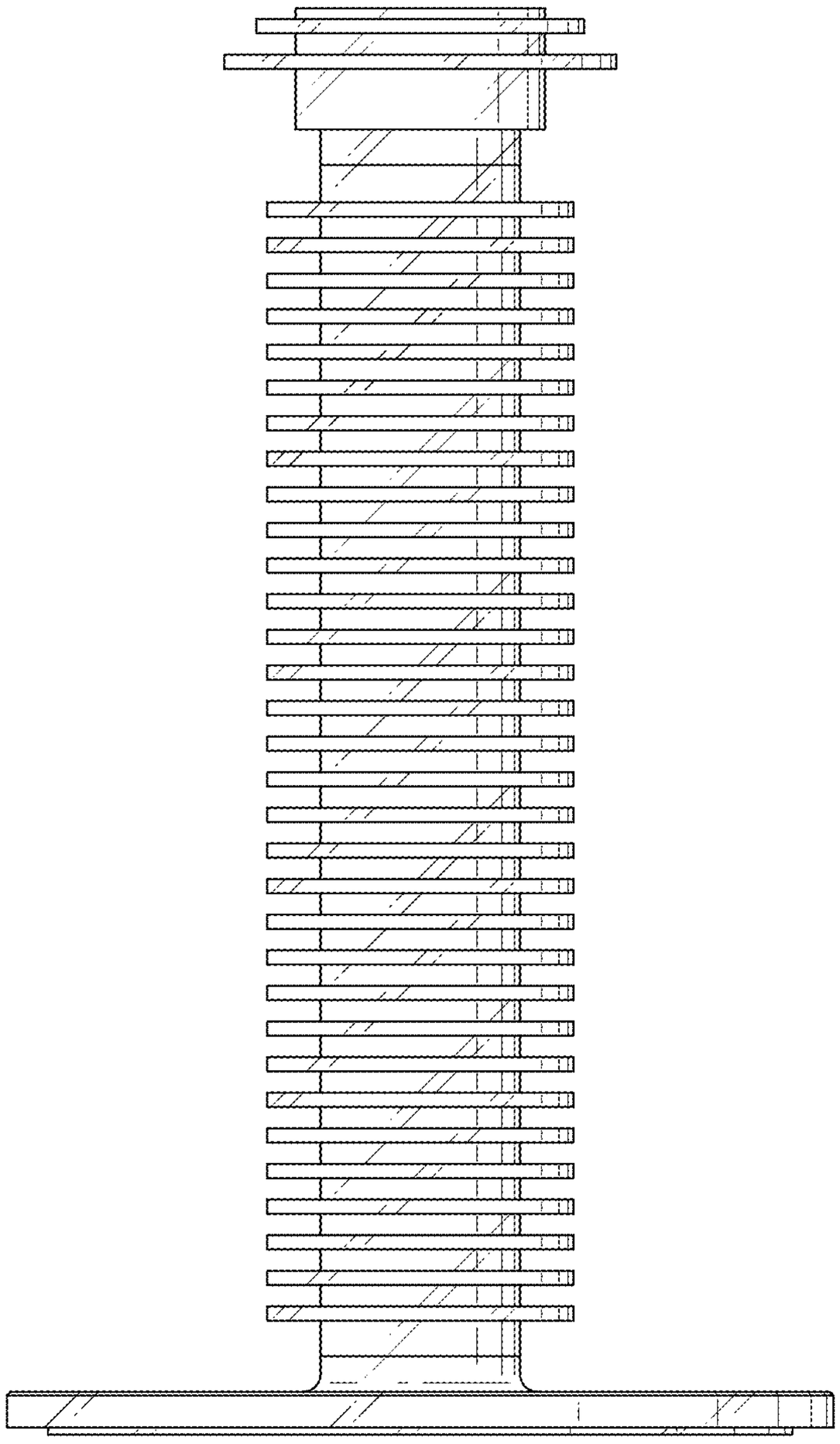

FIG. 3

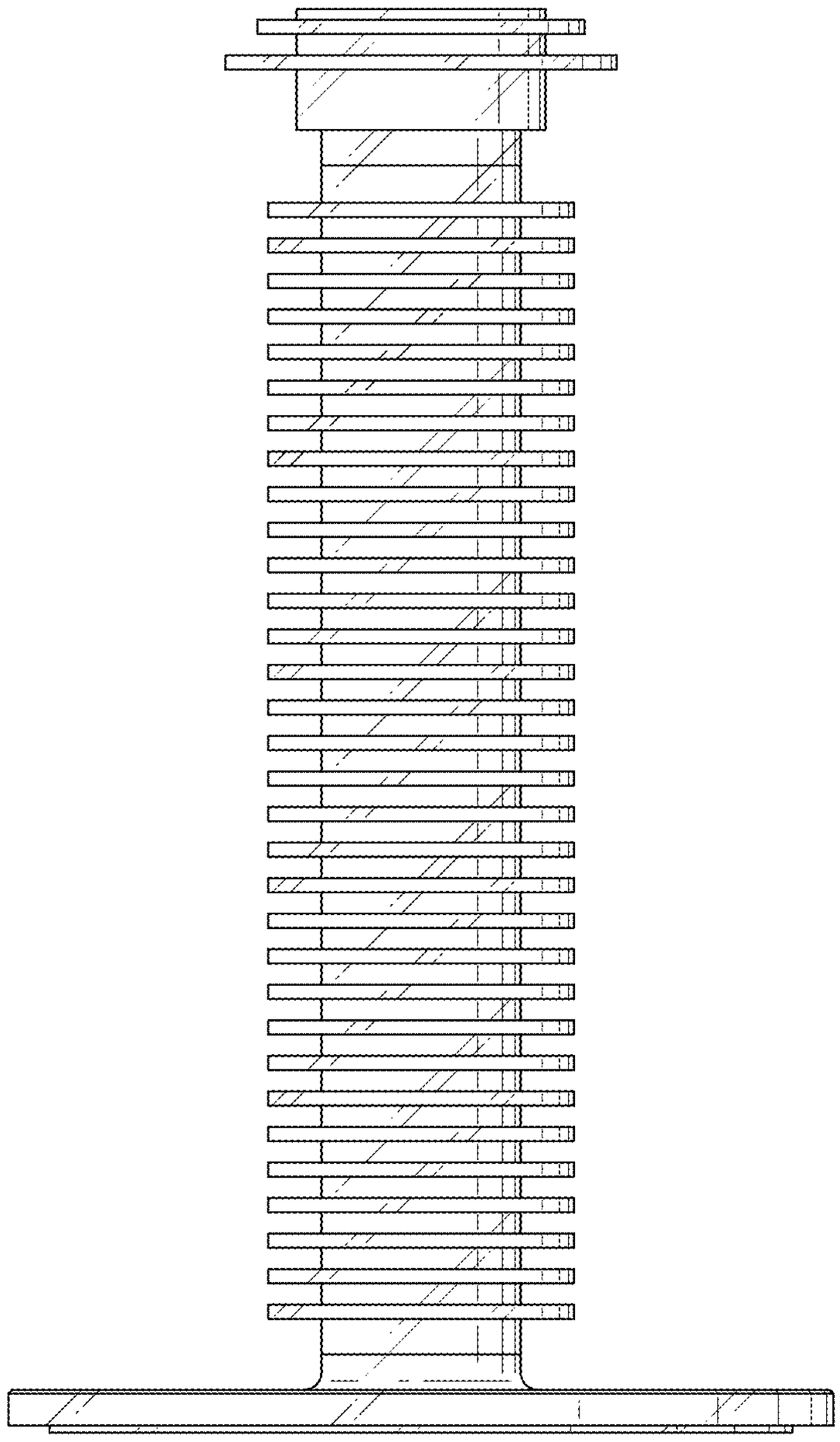

FIG. 4

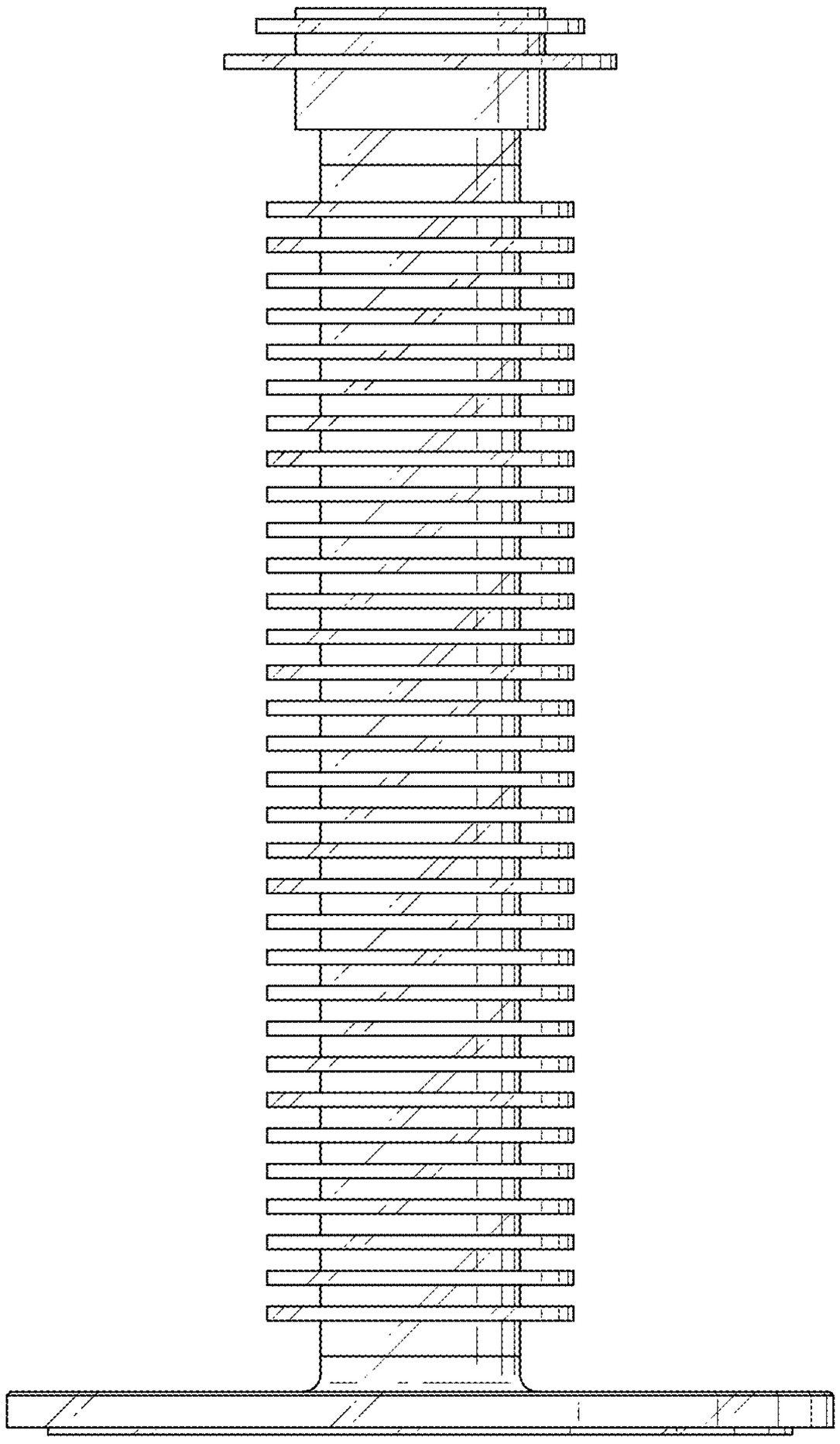

FIG. 5

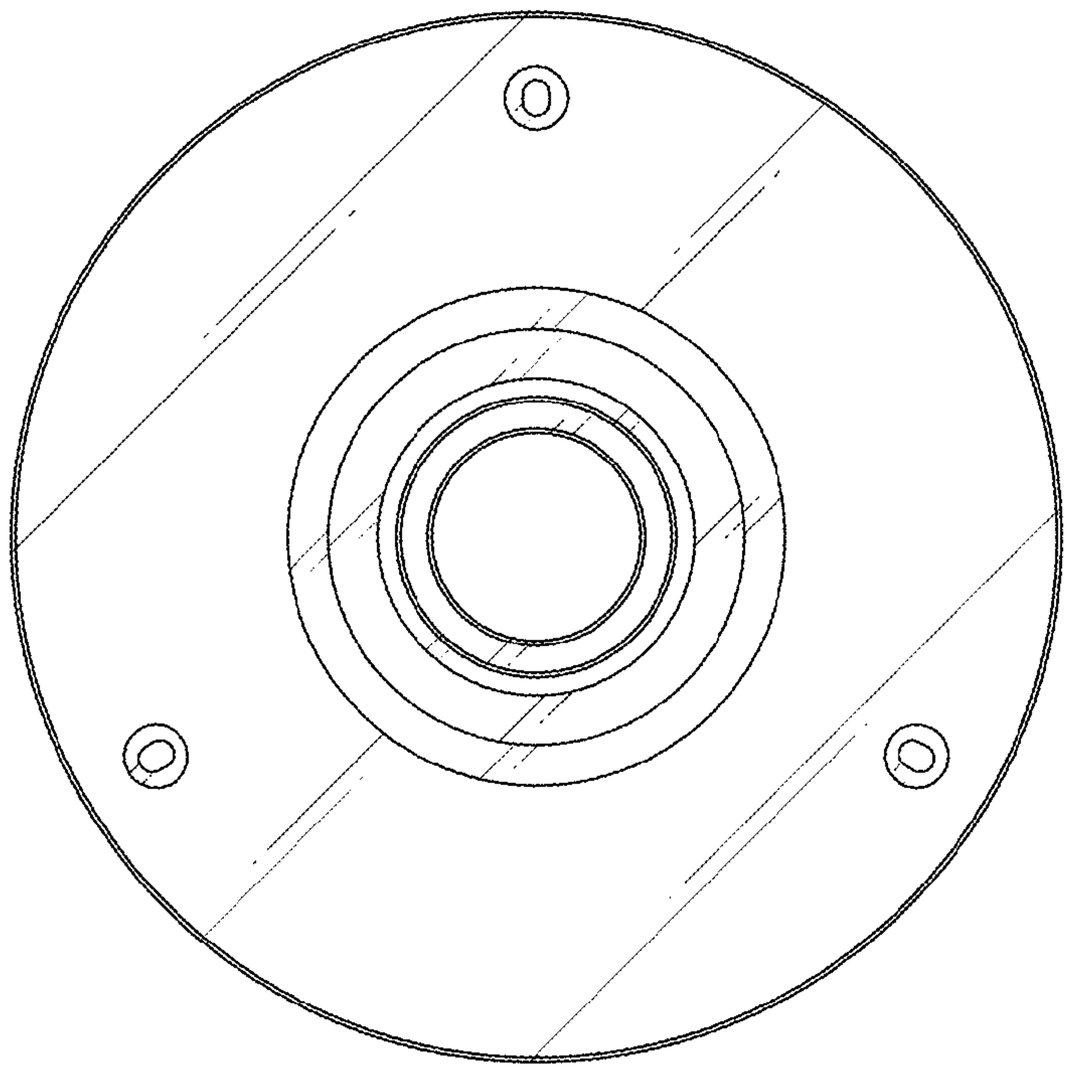

FIG. 6

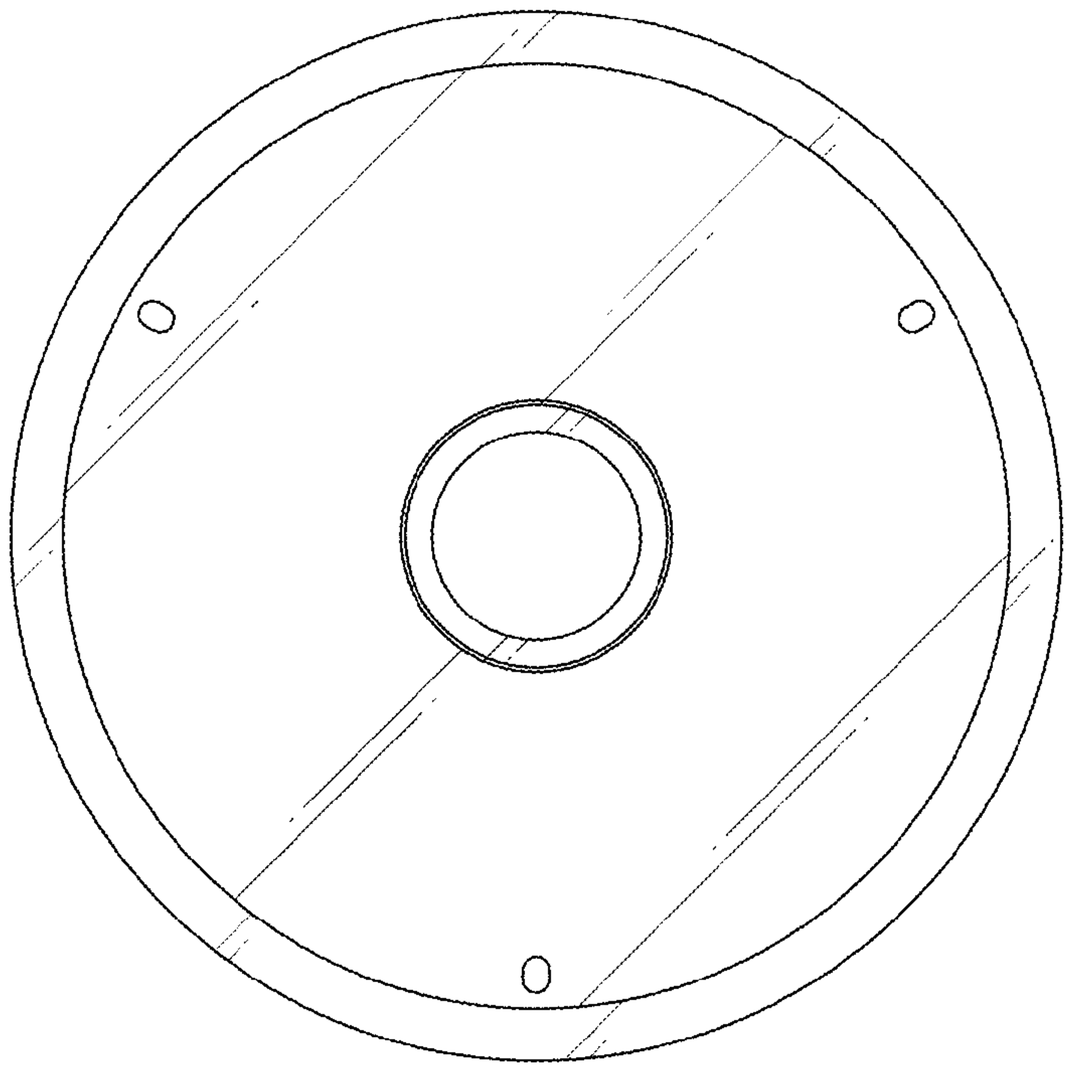

FIG. 7

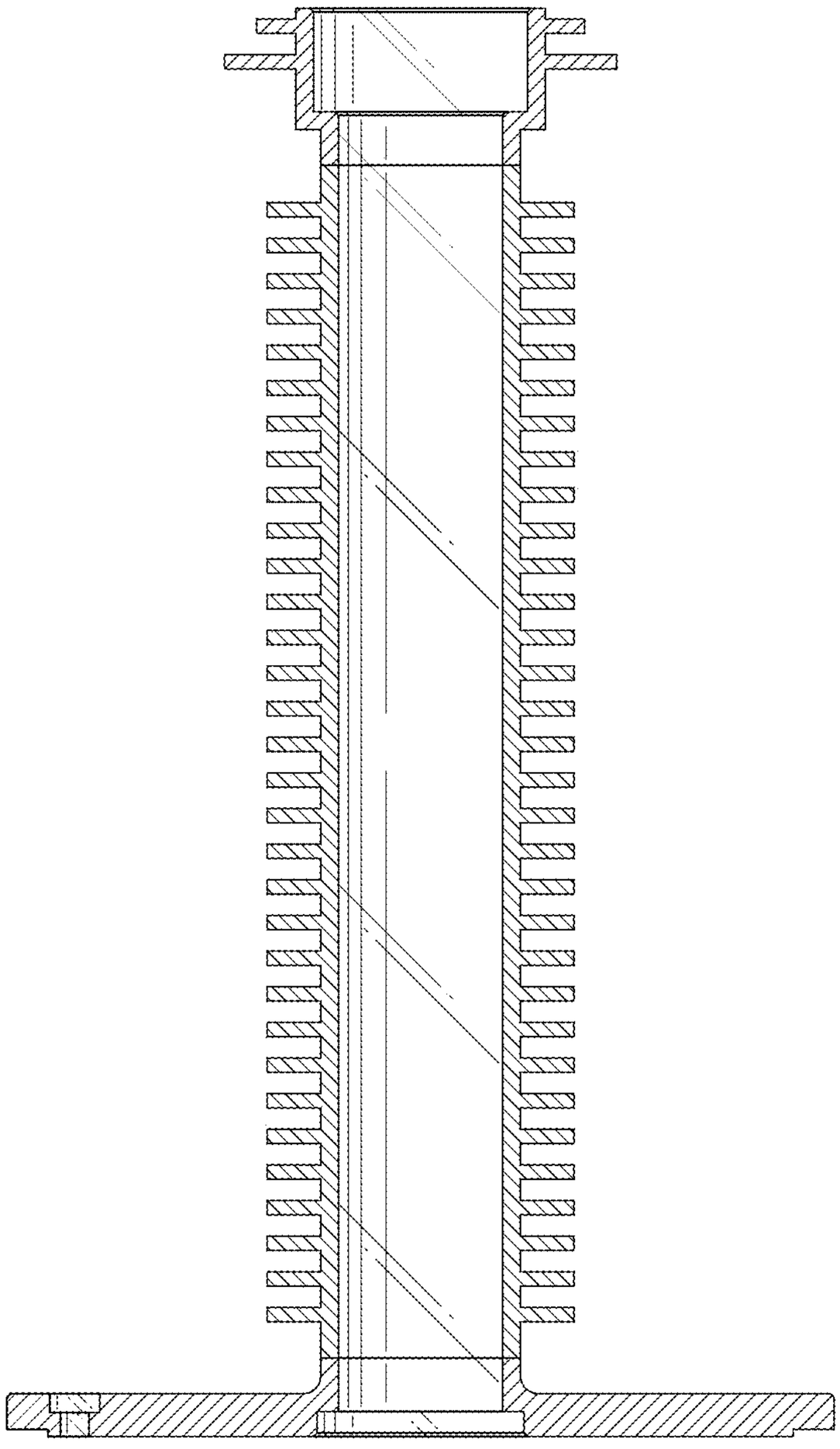

FIG. 8